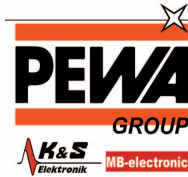




## HI 96726

### Nickel, High Range, Portable Photometer



**PEWA**  
Messtechnik GmbH

Weidenweg 21  
58239 Schwerte

Tel.: 02304-96109-0  
Fax: 02304-96109-88  
E-Mail: [info@pewa.de](mailto:info@pewa.de)  
Homepage : [www.pewa.de](http://www.pewa.de)

- CAL CHECK™
- User calibration
- Certified calibration and verification standards
- BEPS (Battery Error Prevention System)
- TIMER function
- Auto shut-off
- GLP Features

Nickel is commonly utilized by the electroplating industry in processes utilizing stainless steel, cobalt or nickel alloys.

Nickel is also used in batteries, fuel cells and hydrogenation of vegetable oils in the food industry.

The HI 96726 measures the Nickel content in water and wastewater. This meter uses an exclusive positive-locking system to ensure that the cuvette is in the same place every time it is placed into the measurement cell.

The cuvette has a very important role because it is an optical element and thus requires particular attention. It is important that both, the measurement and the calibration (zeroing) cuvettes, are optically identical to provide the same measurement conditions.

#### Order Information:

**HI 96726** is supplied with sample cuvettes with caps (2), 9V battery and instruction manual.

**HI 96726C** includes photometer, sample cuvettes with caps (2 ea.), 9V battery, scissors, cloth for wiping cuvettes, instrument quality certificate, instruction manual and rigid carrying case.

Specifications	Accessories	Downloads
----------------	-------------	-----------

Range	0.00 to 7.00 g/L	
Resolution	0.01 g/L	
Accuracy	±0.07 g/L ±4% @ 25°C	
Light Source	Tungsten lamp	
Light Detector	Silicon photocell with narrow band interference filter @ 575 nm	
Environment	0 to 50°C (32 to 122°F); RH max 95% non-condensing	
Power Supply	(1) 9V battery	
Auto-off	After 10 minutes of non-use in measurement mode; after 1 hour of non-use in calibration mode; with last reading reminder.	
Dimensions	192 x 104 x 69 mm (7.6 x 4.1 x 2.7")	
Weight	360 g (12.7 oz.)	
Method	Adaptation of the photometric method.	